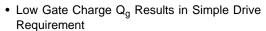


K2695-01-VB Datasheet

N-Channel 700V (D-S) Super Junction Power MOSFET

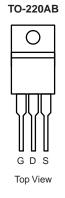
PRODUCT SUMMARY					
V _{DS} (V)	700				
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	1.1			
Q _g (Max.) (nC)	15				
Q _{gs} (nC)	3				
Q _{gd} (nC)	6				
Configuration	Single				

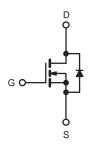
FEATURES





- Improved Gate, Avalanche and Dynamic dV/dt
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Compliant to RoHS directive 2002/95/EC





N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T _C = 25 °C, unless otherwise noted						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	700	V	
Gate-Source Voltage			V _{GS}	± 30	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	
Continuous Drain Current ^e	V _{GS} at 10 V	T _C = 25 °C	1	5		
Continuous Drain Current	VGS at 10 V	T _C = 100 °C	I _D	4	Α	
Pulsed Drain Current ^a			I _{DM}	16		
Linear Derating Factor				1.67/0.8/0.3	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	120	mJ	
Repetitive Avalanche Current ^a			I _{AR}	34	Α	
Repetitive Avalanche Energy ^a			E _{AR}	17	mJ	
Maximum Power Dissipation T _C = 25 °C			P_{D}	205/35/30	W	
Peak Diode Recovery dV/dt ^c			dV/dt	4.5	V/ns	
Operating Junction and Storage Temperature Range			T_J , T_{stg}	- 55 to + 150	°C	
oldering Recommendations (Peak Temperature) ^d for 10 s				300		
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
Woulding Forque				1.1	N · m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Starting T $_J$ = 25 °C, L = 24 mH, R $_G$ = 25 Ω , I $_{AS}$ = 3.2 A (see fig. 12). c. I $_{SD}$ ≤ 3.2 A, dl/dt ≤ 90 A/ μ s, V $_{DD}$ ≤ V $_{DS}$, T $_J$ ≤ 150 °C.

- d. 1.6 mm from case.
- e. Drain current limited by maximum junction temperature.



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-	62	°C/W		
Maximum Junction-to-Case (Drain)	R _{thJC}	-	3.6/1.2/0.6	C/VV		

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	Reference to 25 °C, I _D = 1 mA ^d		0.6	-	mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 30 V	ı	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		= 700 V, V _{GS} = 0 V V, V _{GS} = 0 V, T _J = 125 °C	-	-	10 100	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 2.5 A ^b	-	1.1	-	Ω
Forward Transconductance	9 _{fs}	V _{DS}	= 50 V, I _D = 2.5 A	8	-	-	S
Dynamic		1			l	l.	<u>I</u>
Input Capacitance	C _{iss}		V _{GS} = 0 V,		320	-	
Output Capacitance	C _{oss}		$V_{DS} = 25 \text{ V},$	-	75	-	1
Reverse Transfer Capacitance	C _{rss}	f = 1	f = 1.0 MHz, see fig. 5		4	-	_
Output Canacitanas	C _{oss}		V _{DS} = 1.0 V, f = 1.0 MHz	-	500	-	- pF -
Output Capacitance		$V_{GS} = 0 V$	V _{DS} = 520 V, f = 1.0 MHz	-	83	-	
Effective Output Capacitance	Coss eff.		V _{DS} = 0 V to 520 V ^c	ı	14	-	
Total Gate Charge	Q_g			-	-	15	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		-	-	3	
Gate-Drain Charge	Q_{gd}	see fig. 6 and 13 ^b		-	-	6	1
Turn-On Delay Time	t _{d(on)}			-	18	-	
Rise Time	t _r		$V_{DD} = 325 \text{ V}, I_D = 3.2 \text{ A}$		40	-	1
Turn-Off Delay Time	t _{d(off)}	$R_G = 9.1 \Omega, R_D = 62 \Omega,$ see fig. 10^b		-	50	-	ns -
Fall Time	t _f		j		30	-	
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	showing the	/ :/		-	5	- A
Pulsed Diode Forward Current ^a	I _{SM}	p - n junction diode		-	-	16	
Body Diode Voltage	V_{SD}	T _J = 25 °C, I _S = 3.2 A, V _{GS} = 0 V ^b		-	-	1.5	V
Body Diode Reverse Recovery Time	t _{rr}	- T _J = 25 °C, I _F = 3.2 A, dI/dt = 100 A/μs ^b		-	180	-	ns
Body Diode Reverse Recovery Charge	Q_{rr}			-	2.1	3.2	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)				L _D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 µs; duty cycle \leq 2 %.
- c. C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .
- d. t = 60 s, f = 60 Hz.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

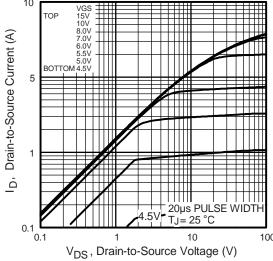


Fig. 1 - Typical Output Characteristics

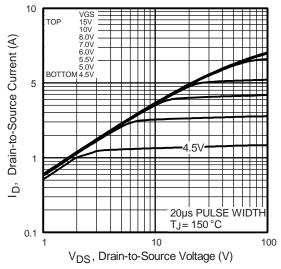


Fig. 2 - Typical Output Characteristics

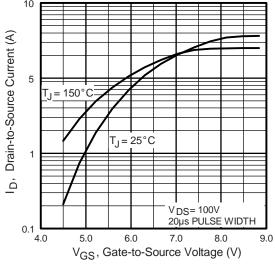


Fig. 3 - Typical Transfer Characteristics

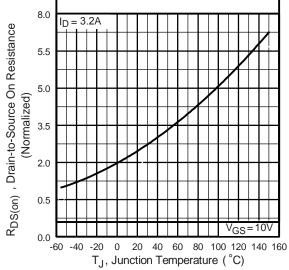


Fig. 4 - Normalized On-Resistance vs. Temperature



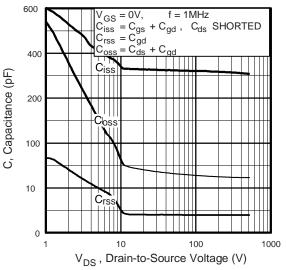


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

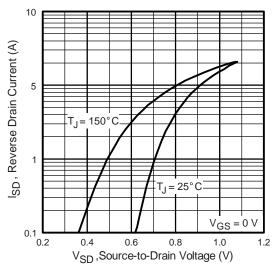


Fig. 7 - Typical Source-Drain Diode Forward Voltage

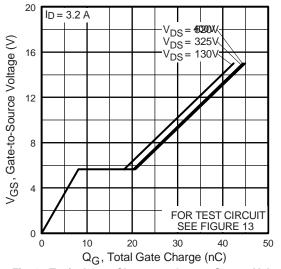


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

4

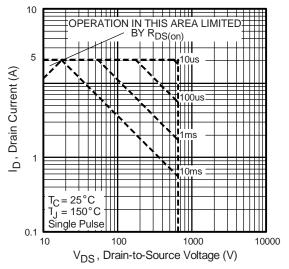


Fig. 8 - Maximum Safe Operating Area



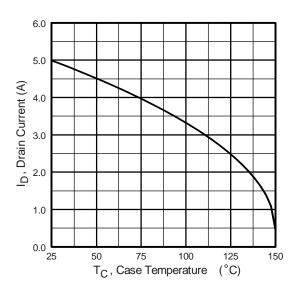


Fig. 9 - Maximum Drain Current vs. Case Temperature

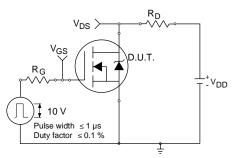


Fig. 10a - Switching Time Test Circuit

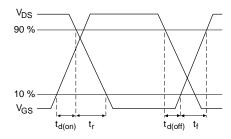


Fig. 10b - Switching Time Waveforms

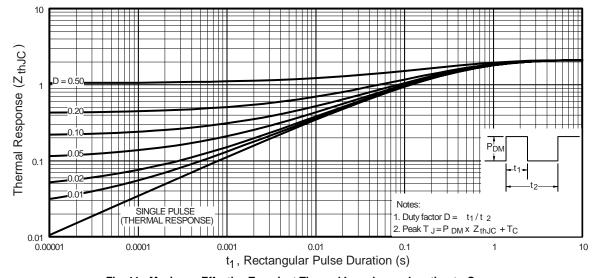


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

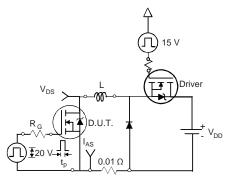


Fig. 12a - Unclamped Inductive Test Circuit

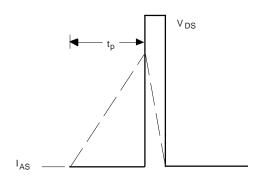


Fig. 12b - Unclamped Inductive Waveforms



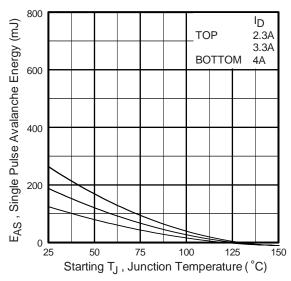


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

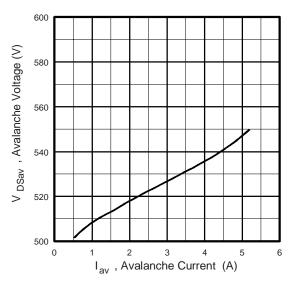


Fig. 12d - Typical Drain-to Source Voltage vs. Avalanche Current

6

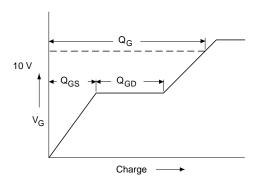


Fig. 13a - Basic Gate Charge Waveform

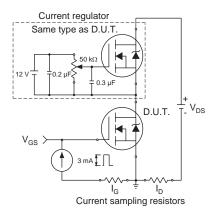
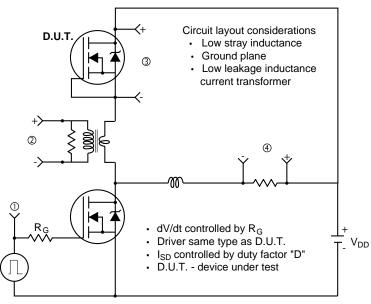


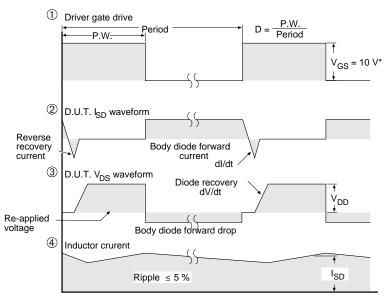
Fig. 13b - Gate Charge Test Circuit



7

Peak Diode Recovery dV/dt Test Circuit



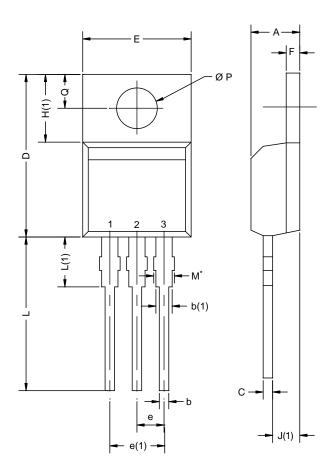


* $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel



TO-220AB



	MILLIN	IETERS	INC	HES		
DIM.	MIN.	MAX.	MIN.	MAX.		
А	4.25	4.65	0.167	0.183		
b	0.69	1.01	0.027	0.040		
b(1)	1.20	1.73	0.047	0.068		
С	0.36	0.61	0.014	0.024		
D	14.85	15.49	0.585	0.610		
Е	10.04	10.51	0.395	0.414		
е	2.41	2.67	0.095	0.105		
e(1)	4.88	5.28	0.192	0.208		
F	1.14	1.40	0.045	0.055		
H(1)	6.09	6.48	0.240	0.255		
J(1)	2.41	2.92	0.095	0.115		
L	13.35	14.02	0.526	0.552		
L(1)	3.32	3.82	0.131	0.150		
ØΡ	3.54	3.94	0.139	0.155		
Q	2.60	3.00	0.102	0.118		
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471						

Notes

 $^{^{\}star}$ M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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